


<b>Search Notes</b>  	<b>Application/Control No.</b>  10509461	<b>Applicant(s)/Patent Under Reexamination</b>  VAN DEN OETELAAR ET AL.
	<b>Examiner</b>  Heyi, Henok G	<b>Art Unit</b>  2609

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
East text searches have been done. 369/94, 275.1 (text search only - see search report printout). I have also relied on the international search report.	06/05/2007	Henok Heyi
Search Updated.	07/17/2008	Henok Heyi
Search updated.	10/02/2008	Henok Heyi
Search updated.	04/23/2009	Henok Heyi

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/HENOK G HEYI/ Examiner.Art Unit 2627	
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